


<b>Search Notes</b> 	<b>Application/Control No.</b> 10519100	<b>Applicant(s)/Patent Under Reexamination</b> LERICHE ET AL.
	<b>Examiner</b> YI CHEN	<b>Art Unit</b> 2142

SEARCHED			
Class	Subclass	Date	Examiner
709	203	9/2/2008	Yi Chen

SEARCH NOTES		
Search Notes	Date	Examiner
Full text search of US patents, US-pubs, and EPO, JPO, Derwent and IBM-TDB databases	9/12/2008	Yi Chen
Assignee Search	9/13/2008	Yi Chen
Inventor name search	9/12/2008	Yi Chen

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

--	--